Current Trends and Future Perspectives on Computer Vision and Pattern Recognition

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Message from the Guest Editors

Dear Colleagues,

Recent advancements in Computer Vision and Pattern Recognition have accelerated the development of intelligent applications for numerous industries and domains. Such solutions are not only seamlessly integrated in the environment, but typically have large adaptability for unexpected conditions, which increases their usefulness for real-world problems. Recent advances in Computer Vision and Pattern Recognition have had many successes but also have several limitations and there is limited understanding of their inner workings. It is remains a major challenge in the deployment of Computer Vision and Pattern Recognition algorithms in real-world scenarios. Therefore, this paper, on the Current Trends and Future Perspectives on Computer Vision and Pattern Recognition, seeks to collect the most recent approaches and findings, as well as discuss the current challenges of Computer Vision and Pattern Recognition solutions for a wide variety of applications. We expect this Special Issue to tackle the research concerns in the closely linked fields of Computer Vision and Pattern Recognition, such as Machine Learning, Data Mining, Computer Vision and Image Processing.

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Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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